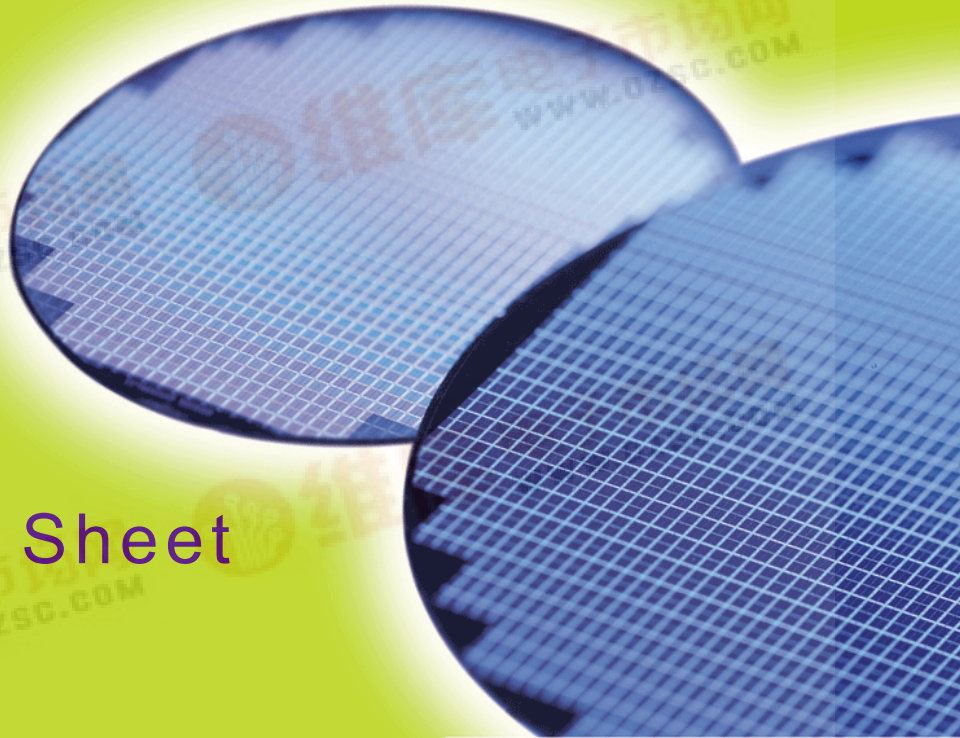


[www.dzsc.com](#)
HY[B/I]39S256[40/80/16]0FT(L)
HY[B/I]39S256[40/80/16]0FE(L)
HYB39S256[40/80/16]0FF(L)
HYB39S256407FE

*256-MBit Synchronous DRAM
SDRAM*

Internet Data Sheet

Rev. 1.42



HY[B/I]39S256[40/80/16][0/7]F[E/T/F](L)
256-MBit Synchronous DRAM

HY[B/I]39S256[40/80/16]0FT(L), HY[B/I]39S256[40/80/16]0FE(L), HYB39S256[40/80/16]0FF(L), HYB39S256407FE	
Revision History: 2007-09, Rev. 1.42	
Page	Subjects (major changes since last revision)
All	Adapted internet edition
7	Corrected SDRAM organization for x4 in Table 4
Previous Revision: 2007-09, Rev. 1.41	
All	Editorial Change
4	Corrected HYB39S256407FF-7 to HYP39S256407FE-7
Previous Revision: 2007-04, Rev. 1.40	
4	Corrected HYB39S256400FE-7 to HYB39S256400FF-7
Previous Revision: 2007-03, Rev. 1.30	

We Listen to Your Comments

Any information within this document that you feel is wrong, unclear or missing at all?

Your feedback will help us to continuously improve the quality of this document.

Please send your proposal (including a reference to this document) to:

techdoc@qimonda.com

HY[B/I]39S256[40/80/16][0/7]F[E/T/F](L)
256-MBit Synchronous DRAM

1 Overview

This chapter lists all main features of the product family HYB39S256[400/800/160]F[E/T/F](L) and the ordering information.

1.1 Features

- Fully Synchronous to Positive Clock Edge
- 0 to 70 °C Standard Operating Temperature
- -40 to 85 °C Industrial Operating Temperature
- Four Banks controlled by BA0 & BA1
- Programmable CAS Latency: 2 & 3
- Programmable Wrap Sequence: Sequential or Interleave
- Programmable Burst Length: 1, 2, 4, 8 and full page
- Multiple Burst Read with Single Write Operation
- Automatic and Controlled Precharge Command
- Data Mask for Read / Write control (x4, x8)
- Data Mask for Byte Control (x16)
- Auto Refresh (CBR) and Self Refresh
- Power Down and Clock Suspend Mode
- 8192 refresh cycles / 64 ms (7.8 μ s)
- Random Column Address every CLK (1-N Rule)
- Single 3.3 V \pm 0.3 V Power Supply
- LVTTL Interface versions
- Packages:
 - P(G)–TSOPII–54 (400mil width)
 - PG–TFBGA–54

TABLE 1
Performance

Product Type Speed Code			-6	-7	Unit
Speed Grade			PC166–333	PC133–222	—
Max. Clock Frequency	@CL3	f_{CK3}	166	143	MHz
		t_{CK3}	6	7	ns
		t_{AC3}	5.4	5.4	ns
	@CL2	t_{CK2}	7.5	7.5	ns
		t_{AC2}	5.4	5.4	ns



HY[B/I]39S256[40/80/16][0/7]F[E/T/F](L)
256-MBit Synchronous DRAM

1.2 Description

The HYB39S256[400/800/160]F[E/T/F](L) are four bank Synchronous DRAMs organized as 4 banks x 16 MBit x4, 4 banks x 8 MBit x8 and 4 banks x 4 Mbit x16 respectively. These synchronous devices achieve high speed data transfer rates for CAS latencies by employing a chip architecture that prefetches multiple bits and then synchronizes the output data to a system clock. The chip is fabricated with Qimonda's advanced 0.11- μ m 256-MBit DRAM process technology.

The device is designed to comply with all industry standards set for synchronous DRAM products, both electrically and mechanically. All of the control, address, data input and output circuits are synchronized with the positive edge of an externally supplied clock.

Operating the four memory banks in an interleave fashion allows random access operation to occur at a higher rate than is possible with standard DRAMs. A sequential and gapless data rate is possible depending on burst length, CAS latency and speed grade of the device.

Auto Refresh (CBR) and Self Refresh operation are supported. These devices operate with a single 3.3 V \pm 0.3 V power supply. All 256-Mbit components are available in P(G)-TSOPII-54 and PG-TFBGA-54 packages.

TABLE 2
Ordering Information for RoHS Compliant Products

Product Type	Speed Grade	Description	Package	Note
Standard Operating Temperature				
HYB39S256407FE-7	PC133-222	143MHz 64M x 4 SDRAM	PG-TFBGA-54	1)
HYB39S256400FF-7			PG-TFBGA-54	
HYB39S256400FE-7			PG-TSOPII-54	
HYB39S256400FFL-7			PG-TFBGA-54	
HYB39S256400FEL-7			PG-TSOPII-54	
HYB39S256800FF-7		143MHz 32M x 8 SDRAM	PG-TFBGA-54	
HYB39S256800FE-7			PG-TSOPII-54	
HYB39S256800FFL-7			PG-TFBGA-54	
HYB39S256800FEL-7			PG-TSOPII-54	
HYB39S256160FF-7		143MHz 16M x 16 SDRAM	PG-TFBGA-54	
HYB39S256160FE-7			PG-TSOPII-54	
HYB39S256160FFL-7			PG-TFBGA-54	
HYB39S256160FEL-7			PG-TSOPII-54	
HYB39S256160FF-6		166MHz 16M x 16 SDRAM	PG-TFBGA-54	
HYB39S256160FE-6			PG-TSOPII-54	
HYB39S256160FFL-6			PG-TFBGA-54	
HYB39S256160FEL-6	PG-TSOPII-54			
Industrial Operating Temperature				
HYI39S256800FE-7	PC166-333	143MHz 32M x 8 SDRAM	PG-TSOPII-54	1)
HYI39S256160FE-7		143MHz 16M x 16 SDRAM		

1) RoHS Compliant Product: Restriction of the use of certain hazardous substances (RoHS) in electrical and electronic equipment as defined in the directive 2002/95/EC issued by the European Parliament and of the Council of 27 January 2003. These substances include mercury, lead, cadmium, hexavalent chromium, polybrominated biphenyls and polybrominated biphenyl ethers.

HY[B/I]39S256[40/80/16][0/7]F[E/T/F](L)
256-MBit Synchronous DRAM**TABLE 3**
Ordering Information for Lead-Containing Products

Product Type	Speed Grade	Description	Package
Standard Operating Temperature			
HYB39S256400FT-7	PC133-222	143MHz 64M x 4 SDRAM	P-TSOP11-54
HYB39S256400FTL-7			
HYB39S256800FT-7		143MHz 32M x 8 SDRAM	
HYB39S256800FTL-7			
HYB39S256160FT-7		143MHz 16M x 16 SDRAM	
HYB39S256160FTL-7			
HYB39S256160FT-6		166MHz 16M x 16 SDRAM	
Industrial Operating Temperature			
HYI39S256800FT-7	PC133-222	143MHz 32M x 8 SDRAM	P-TSOP11-54
HYI39S256160FT-7		143MHz 16M x 16 SDRAM	

Note: For product nomenclature see **Chapter 6** of this data sheet



2 Configuration

This chapter contains the pin configuration table, the TSOP and FBGA package drawing, and the block diagrams for the $\times 4$, $\times 8$, $\times 16$ organization of the SDRAM.

2.1 Pin Description

Listed below are the pin configurations sections for the various signals of the SDRAM.

TABLE 4
Pin Configuration of the SDRAM

Ball No.	Name	Pin Type	Buffer Type	Function
Clock Signals $\times 4/\times 8/\times 16$ Organization				
38, 2F	CLK	I	LVTTTL	Clock Signal CK
37, 3F	CKE	I	LVTTTL	Clock Enable
Control Signals $\times 4/\times 8/\times 16$ Organization				
18, 8F	$\overline{\text{RAS}}$	I	LVTTTL	Row Address Strobe (RAS), Column Address Strobe (CAS), Write Enable (WE)
17, 7F	$\overline{\text{CAS}}$	I	LVTTTL	
16, 9F	$\overline{\text{WE}}$	I	LVTTTL	
19, 9G	$\overline{\text{CS}}$	I	LVTTTL	Chip Select
Address Signals $\times 4/\times 8/\times 16$ Organization				
20, 7G	BA0	I	LVTTTL	Bank Address Signals 1:0
21, 8G	BA1	I	LVTTTL	
23, 7H	A0	I	LVTTTL	Address Signal 12:0, Address Signal 10/Auto precharge
24, 8H	A1	I	LVTTTL	
25, 8J	A2	I	LVTTTL	
26, 7J	A3	I	LVTTTL	
29, 3J	A4	I	LVTTTL	
30, 2J	A5	I	LVTTTL	
31, 3H	A6	I	LVTTTL	
32, 2H	A7	I	LVTTTL	
33, 1H	A8	I	LVTTTL	
34, 3G	A9	I	LVTTTL	
22, 9H	A10	I	LVTTTL	
35, 2G	A11	I	LVTTTL	
36, 1G	A12	I	LVTTTL	



HY[B/I]39S256[40/80/16][0/7]F[E/T/F](L)
256-MBit Synchronous DRAM

Ball No.	Name	Pin Type	Buffer Type	Function
Data Signals ×4 Organization				
5, 8B	DQ0	I/O	LVTTTL	Data Signal Bus 3:0
11, 8D	DQ1	I/O	LVTTTL	
44, 2D	DQ2	I/O	LVTTTL	
50, 2B	DQ3	I/O	LVTTTL	
Data Signals ×8 Organization				
2, 8A	DQ0	I/O	LVTTTL	Data Signal Bus 7:0
5, 8B	DQ1	I/O	LVTTTL	
8, 8C	DQ2	I/O	LVTTTL	
11, 8D	DQ3	I/O	LVTTTL	
44, 2D	DQ4	I/O	LVTTTL	
47, 2C	DQ5	I/O	LVTTTL	
50, 2B	DQ6	I/O	LVTTTL	
53, 2A	DQ7	I/O	LVTTTL	
Data Signals ×16 Organization				
2, 8A	DQ0	I/O	LVTTTL	Data Signal Bus 15:0
4, 9B	DQ1	I/O	LVTTTL	
5, 8B	DQ2	I/O	LVTTTL	
7, 9C	DQ3	I/O	LVTTTL	
8, 8C	DQ4	I/O	LVTTTL	
10, 9D	DQ5	I/O	LVTTTL	
11, 8D	DQ6	I/O	LVTTTL	
13, 9E	DQ7	I/O	LVTTTL	
42, 1E	DQ8	I/O	LVTTTL	
44, 2D	DQ9	I/O	LVTTTL	
45, 1D	DQ10	I/O	LVTTTL	
47, 2C	DQ11	I/O	LVTTTL	
48, 1C	DQ12	I/O	LVTTTL	
50, 2B	DQ13	I/O	LVTTTL	
51, 1B	DQ14	I/O	LVTTTL	
53, 2A	DQ15	I/O	LVTTTL	
Data Mask ×4/×8 Organization				
39, 1F	DQM	I/O	LVTTTL	Data Mask
Data Mask ×16 Organization				
39, 1F	UDQM	I/O	LVTTTL	Data Mask Upper Byte
15, 8E	LDQM	I/O	LVTTTL	Data Mask Lower Byte
Power Supplies ×4/×8/×16 Organization				
3B, 3D, 7A, 7C	V _{DDQ}	PWR	–	Power Supply



HY[B/I]39S256[40/80/16][0/7]F[E/T/F](L)
256-MBit Synchronous DRAM

Ball No.	Name	Pin Type	Buffer Type	Function
7E, 9A, 9J	V_{DD}	PWR	–	Power Supply
3A, 3C, 7B, 7D	V_{SSQ}	PWR	–	Power Supply Ground for DQs
1J, 1A, 3E	V_{SS}	PWR	–	Power Supply Ground
Not connected ×4 Organization				
2, 4, 7, 8, 10, 13, 15, 40, 42, 45, 47, 48, 51, 53, 1B, 1C, 1D, 1E, 2A, 2C, 2E, 8A, 8C, 8E, 9B, 9C, 9D, 9E	NC	NC	–	Not connected
Not connected ×8 Organization				
7, 10, 13, 15, 40, 42, 45, 48, 51, 1B, 1C, 1D, 1E, 2E, 8E, 9B, 9C, 9D, 9E	NC	NC	–	Not connected
Not connected ×16 Organization				
40, 2E	NC	NC	–	Not connected

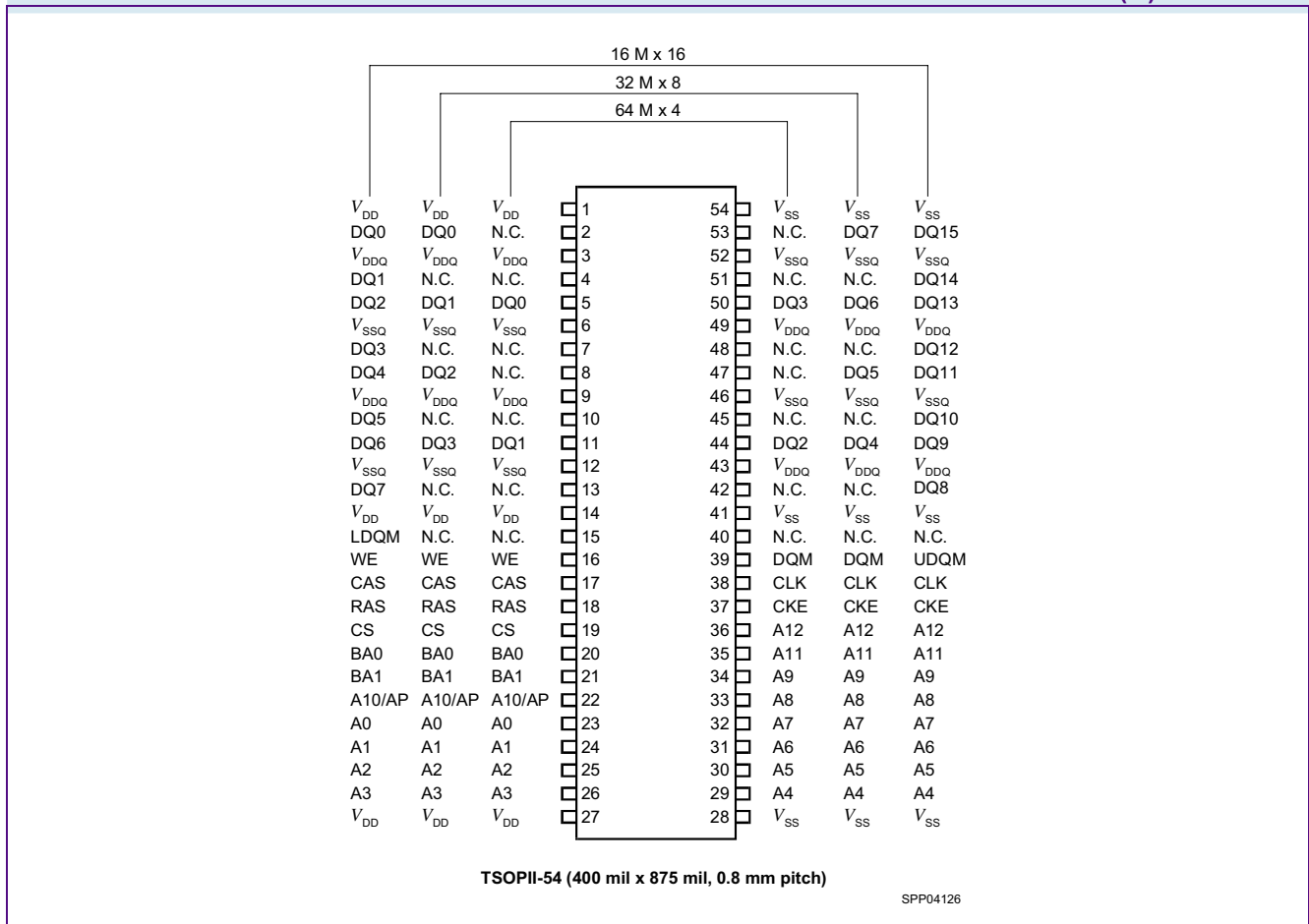


HY[B/I]39S256[40/80/16][0/7]F[E/T/F](L)
256-MBit Synchronous DRAM

2.2 Package P(G)-TSOPII-54

Listed below are the pin outs of the TSOP package.

FIGURE 1
Pinouts P(G)-TSOPII-54





2.3 Package PG-TFBGA-54

Listed below are the ball outs of the TFBGA package.

- **Figure 2 “Ballout for ×16 components, TFBGA-54 (top view)” on Page 10**
- **Figure 3 “Ballout for ×8 components, TFBGA-54 (top view)” on Page 11**
- **Figure 4 “Ballout for ×4 components, TFBGA-54 (top view)” on Page 12**

FIGURE 2

Ballout for ×16 components, TFBGA-54 (top view)

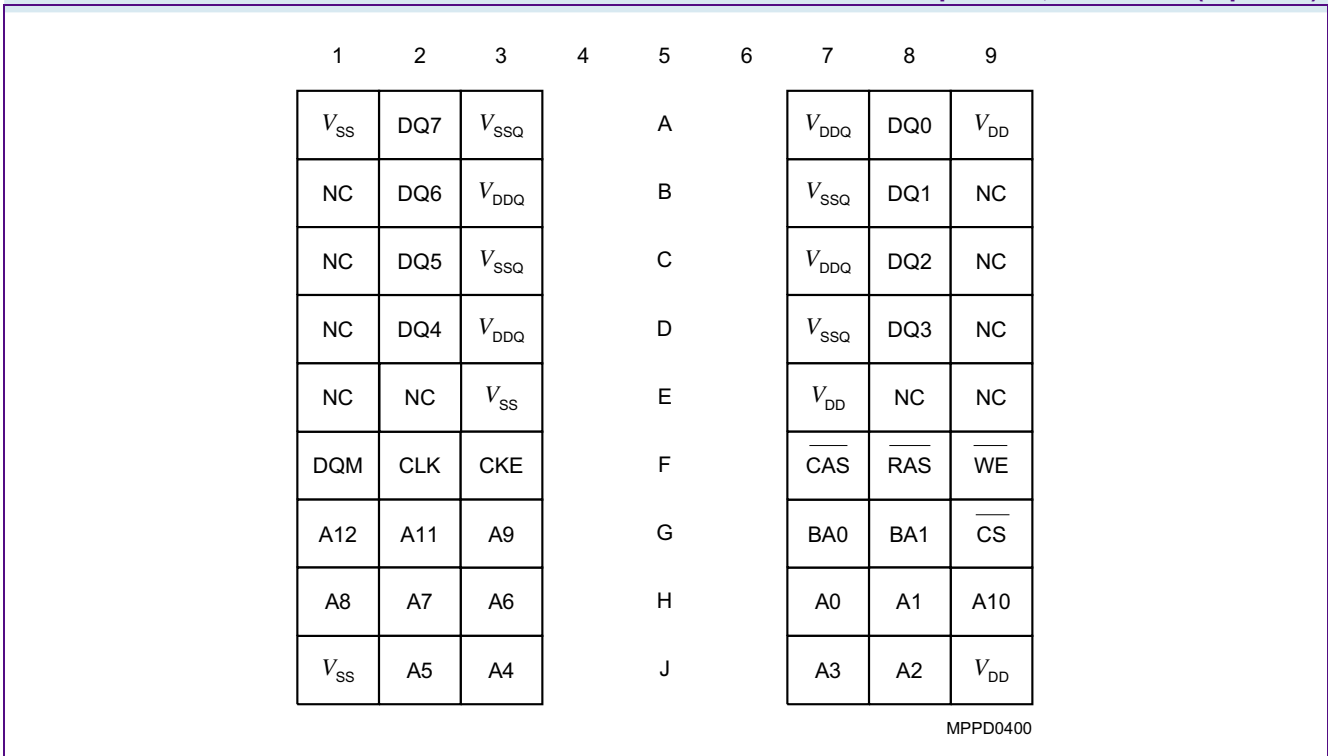
1	2	3	4	5	6	7	8	9
V _{SS}	DQ15	V _{SSQ}		A		V _{DDQ}	DQ0	V _{DD}
DQ14	DQ13	V _{DDQ}		B		V _{SSQ}	DQ2	DQ1
DQ12	DQ11	V _{SSQ}		C		V _{DDQ}	DQ4	DQ3
DQ10	DQ9	V _{DDQ}		D		V _{SSQ}	DQ6	DQ5
DQ8	NC	V _{SS}		E		V _{DD}	LDQM	DQ7
UDQM	CLK	CKE		F		$\overline{\text{CAS}}$	$\overline{\text{RAS}}$	$\overline{\text{WE}}$
A12	A11	A9		G		BA0	BA1	$\overline{\text{CS}}$
A8	A7	A6		H		A0	A1	A10
V _{SS}	A5	A4		J		A3	A2	V _{DD}

MPPD0391



HY[B/I]39S256[40/80/16][0/7]F[E/T/F](L)
256-MBit Synchronous DRAM

FIGURE 3
Ballout for ×8 components, TFBGA-54 (top view)





HY[B/I]39S256[40/80/16][0/7]F[E/T/F](L)
256-MBit Synchronous DRAM

FIGURE 4
Ballout for $\times 4$ components, TFBGA-54 (top view)

1	2	3	4	5	6	7	8	9
V_{SS}	NC	V_{SSQ}		A		V_{DDQ}	NC	V_{DD}
NC	DQ3	V_{DDQ}		B		V_{SSQ}	DQ0	NC
NC	NC	V_{SSQ}		C		V_{DDQ}	NC	NC
NC	DQ2	V_{DDQ}		D		V_{SSQ}	DQ1	NC
NC	NC	V_{SS}		E		V_{DD}	NC	NC
DQM	CLK	CKE		F		$\overline{\text{CAS}}$	$\overline{\text{RAS}}$	$\overline{\text{WE}}$
A12	A11	A9		G		BA0	BA1	$\overline{\text{CS}}$
A8	A7	A6		H		A0	A1	A10
V_{SS}	A5	A4		J		A3	A2	V_{DD}

MPPD0410



3 Functional Description

This chapter contains the functional description.

TABLE 5

Truth Table: Operation Command

Operation	Device State	CKE n-1 ¹⁾²⁾	CKE n ¹⁾²⁾	DQM ¹⁾²⁾	BA0 BA1 ¹⁾²⁾	AP= A10 ¹⁾²⁾	Addr. ¹⁾²⁾	$\overline{\text{CS}}^1$ ²⁾	$\overline{\text{RAS}}^1$ ¹⁾²⁾	$\overline{\text{CAS}}^1$ ²⁾	$\overline{\text{WE}}^1$ ¹⁾²⁾
Bank Active	Idle ³⁾	H	X	X	V	V	V	L	L	H	H
Bank Precharge	Any	H	X	X	V	L	X	L	L	H	L
Precharge All	Any	H	X	X	X	H	X	L	L	H	L
Write	Active ³⁾	H	X	X	V	L	V	L	H	L	L
Write with Auto pre-charge	Active ³⁾	H	X	X	V	H	V	L	H	L	L
Read	Active ³⁾	H	X	X	V	L	V	L	H	L	H
Read with Auto pre-charge	Active ³⁾	H	X	X	V	H	V	L	H	L	H
Mode Register Set	Idle	H	X	X	V	V	V	L	L	L	L
No Operation	Any	H	X	X	X	X	X	L	H	H	H
Burst Stop	Active	H	X	X	X	X	X	L	H	H	L
Device Deselect	Any	H	X	X	X	X	X	H	X	X	X
Auto Refresh	Idle	H	H	X	X	X	X	L	L	L	H
Self Refresh Entry	Idle	H	L	X	X	X	X	L	L	L	H
Self Refresh Exit	Idle (Self Refr.)	L	H	X	X	X	X	H	X	X	X
								L	H	H	X
Power Down/ Clock Suspend Entry	Active or Idle or Burst	H	L	X	X	X	X	H	X	X	X
								L	H	H	H
Power Down/ Clock Suspend Exit	Active or Idle or Burst	L	H	X	X	X	X	H	X	X	X
								L	H	H	H
Data Write/ Output Enable	Active	H	X	L	X	X	X	X	X	X	X
Data Write/ Output Disable	Active	H	X	H	X	X	X	X	X	X	X

1) V = Valid, x = Don't Care, L = Low Level, H = High Level

2) CKE_n signal is input level when commands are provided, CKE_{n-1} signal is input level one clock before the commands are provided.

3) This is the state of the banks designated by BA0, BA1 signals.



HY[B/I]39S256[40/80/16][0/7]F[E/T/F](L)
256-MBit Synchronous DRAM

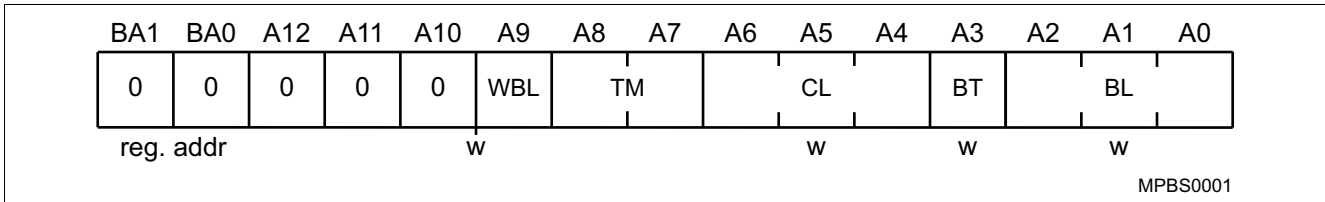


TABLE 6
Mode Register Definition (BA_{1:0} = 00_B)

Field	Bits	Type	Description
BL	2:0	w	Burst Length <i>Note: All other bit combinations are RESERVED.</i> 000 _B 1 001 _B 2 010 _B 4 011 _B 8 111 _B Full Page (Sequential burst type only)
BT	3		Burst Type 0 _B Sequential 1 _B Interleaved
CL	6:4		CAS Latency Number of full clocks from read command to first data valid window. <i>Note: All other bit combinations are RESERVED.</i> 010 _B 2 011 _B 3
TM	8:7		Test Mode <i>Note: All other bit combinations are RESERVED.</i> 00 _B Mode register set
WBL	9		Write Burst Length 0 _B Burst write 1 _B Single bit write
	12:10		Reserved, set to zero



HY[B/I]39S256[40/80/16][0/7]F[E/T/F](L)
256-MBit Synchronous DRAM

TABLE 7
Burst Length and Sequence

Burst Length	Starting Column Address			Order of Accesses Within a Burst	
	A2	A1	A0	Type=Sequential	Type=Interleaved
2			0	0-1	0-1
			1	1-0	1-0
4		0	0	0-1-2-3	0-1-2-3
		0	1	1-2-3-0	1-0-3-2
		1	0	2-3-0-1	2-3-0-1
		1	1	3-0-1-2	3-2-1-0
8	0	0	0	0-1-2-3-4-5-6-7	0-1-2-3-4-5-6-7
	0	0	1	1-2-3-4-5-6-7-0	1-0-3-2-5-4-7-6
	0	1	0	2-3-4-5-6-7-0-1	2-3-0-1-6-7-4-5
	0	1	1	3-4-5-6-7-0-1-2	3-2-1-0-7-6-5-4
	1	0	0	4-5-6-7-0-1-2-3	4-5-6-7-0-1-2-3
	1	0	1	5-6-7-0-1-2-3-4	5-4-7-6-1-0-3-2
	1	1	0	6-7-0-1-2-3-4-5	6-7-4-5-2-3-0-1
	1	1	1	7-0-1-2-3-4-5-6	7-6-5-4-3-2-1-0
FullPage	n			Cn, Cn+1, Cn+2	not supported

Notes

1. For a burst length of two, A1-Ai selects the two-data-element block; A0 selects the first access within the block.
2. For a burst length of four, A2-Ai selects the four-data-element block; A0-A1 selects the first access within the block.
3. For a burst length of eight, A3-Ai selects the eight-data-element block; A0-A2 selects the first access within the block.
4. Whenever a boundary of the block is reached within a given sequence above, the following access wraps within the block.



4 Electrical Characteristics

This chapter lists the electrical characteristics.

4.1 Operating Conditions

This chapter describes the operating conditions.

TABLE 8
Absolute Maximum Ratings

Parameter	Symbol	Limit Values		Unit	Note/ Test Condition
		Min.	Max.		
Input / Output voltage relative to V_{SS}	V_{IN}, V_{OUT}	- 1.0	+4.6	V	–
Voltage on V_{DD} supply relative to V_{SS}	V_{DD}	- 1.0	+4.6	V	–
Voltage on V_{DDQ} supply relative to V_{SS}	V_{DDQ}	- 1.0	+4.6	V	–
Operating Temperature for HYB...	T_A	0	+70	°C	–
Operating Temperature for HYI...	T_A	- 40	+85	°C	–
Storage temperature range	T_{STG}	-55	+150	°C	–
Power dissipation per SDRAM component	P_D	–	1	W	–
Data out current (short circuit)	I_{OUT}	–	50	mA	–

Attention: Stresses above the max. values listed here may cause permanent damage to the device. Exposure to absolute maximum rating conditions for extended periods may affect device reliability. Maximum ratings are absolute ratings; exceeding only one of these values may cause irreversible damage to the integrated circuit.



HY[B/I]39S256[40/80/16][0/7]F[E/T/F](L)
256-MBit Synchronous DRAM

TABLE 9
DC Characteristics

Parameter	Symbol	Values		Unit	Note ¹⁾ / Test Condition
		Min.	Max.		
Supply Voltage	V_{DD}	3.0	3.6	V	2)
I/O Supply Voltage	V_{DDQ}	3.0	3.6	V	2)
Input high voltage	V_{IH}	2.0	$V_{DDQ} + 0.3$	V	2)3)
Input low voltage	V_{IL}	-0.3	+0.8	V	2)3)
Output high voltage ($I_{OUT} = -4.0$ mA)	V_{OH}	2.4	-	V	2)
Output low voltage ($I_{OUT} = 4.0$ mA)	V_{OL}	-	0.4	V	2)
Input leakage current, any input ($0\text{ V} < V_{IN} < V_{DD}$, all other inputs = 0 V)	I_{IL}	-5	+5	μA	-
Output leakage current (DQs are disabled, $0\text{ V} < V_{OUT} < V_{DDQ}$)	I_{OL}	-5	+5	μA	-

- 1) $T_A = 0$ to $70\text{ }^\circ\text{C}$
- 2) All voltages are referenced to V_{SS}
- 3) V_{IH} may overshoot to $V_{DDQ} + 2.0$ V for pulse width of < 4 ns with 3.3 V. V_{IL} may undershoot to -2.0 V for pulse width < 4.0 ns with 3.3 V. Pulse width measured at 50% points with amplitude measured peak to DC reference.

TABLE 10
Input and Output Capacitances

Parameter	Symbol	Values ¹⁾		Unit	Note
		Min.	Max.		
Input Capacitances: CK	C_{I1}	2.5	3.5	pF	2)
Input Capacitance (A0-A12, BA0, BA1, $\overline{\text{RAS}}$, $\overline{\text{CAS}}$, $\overline{\text{WE}}$, $\overline{\text{CS}}$, CKE, DQM)	C_{I2}	2.5	3.8	pF	
Input/Output Capacitance (DQ)	C_{I0}	4.0	6.0	pF	

- 1) Capacitance values are shown for TSOP-54 packages. Capacitance values for TFBGA packages are lower by 0.5 pF
- 2) $T_A = 0$ to $70\text{ }^\circ\text{C}$; $V_{DD}, V_{DDQ} = 3.3\text{ V} \pm 0.3\text{ V}$, $f = 1\text{ MHz}$

TABLE 11
IDD Conditions

Parameter	Symbol
Operating Current One bank active, Burst length = 1	I_{DD1}
Precharge Standby Current in Power Down Mode	I_{DD2P}
Recharge Standby Current in Non-Power Down Mode	I_{DD2N}
No Operating Current Active state (max. 4 banks)	I_{DD3N}
	I_{DD3P}
Burst Operating Current Read command cycling	I_{DD4}
Auto Refresh Current Auto Refresh command cycling	I_{DD5}



HY[B/I]39S256[40/80/16][0/7]F[E/T/F](L)
256-MBit Synchronous DRAM

Parameter	Symbol
Self Refresh Current (standard components) Self Refresh Mode, $CKE=0.2V$, $t_{CK}=\text{infinity}$	I_{DD6}
Self Refresh Current (low power components) Self Refresh Mode, $CKE=0.2V$, $t_{CK}=\text{infinity}$	

TABLE 12

I_{DD} Specifications and Conditions

Symbol		-6	-7	Unit	Note/ Test Condition ¹⁾²⁾
		Max.			
I_{DD1}	$t_{RC} = t_{RC(\text{min})}$, $I_O = 0 \text{ mA}$	100	80	mA	3)4)
I_{DD2P}	$\overline{CS} = V_{IH(\text{min.})}$, $CKE \leq V_{IL(\text{max.})}$	2	2	mA	2)
I_{DD2N}	$\overline{CS} = V_{IH(\text{min.})}$, $CKE \geq V_{IH(\text{min.})}$	26	22	mA	2)
I_{DD3N}	$CS = V_{IH(\text{min.})}$, $CKE \geq V_{IH(\text{min.})}$	40	35	mA	2)
I_{DD3P}	$CS = V_{IH(\text{min.})}$, $CKE \leq V_{IL(\text{max.})}$	5	5	mA	2)
I_{DD4}		65	57	mA	2)3)
I_{DD5}	$t_{RFC} = t_{RFC(\text{min})}$	168	142	mA	5)
	$t_{RFC} = 7.8 \mu\text{s}$	25	25	mA	
I_{DD6}		3	3	mA	Standard components
		1.05	1.05	mA	Low power components ⁶⁾

- 1) Currents values will be added when available.
- 2) $T_A = 0$ to $70 \text{ }^\circ\text{C}$; $V_{SS} = 0 \text{ V}$; V_{DD} , $V_{DDQ} = 3.3 \text{ V} \pm 0.3 \text{ V}$
- 3) These parameters depend on the cycle rate. All values are measured at 166 MHz for -6, at 133 MHz for -7 and -7.5 and at 100 MHz for -8 components with the outputs open. Input signals are changed once during t_{CK} .
- 4) These parameters are measured with continuous data stream during read access and all DQ toggling. CL=3 and BL=4 is assumed and the V_{DDQ} current is excluded.
- 5) $t_{RFC} = t_{RFC(\text{min})}$ "burst refresh", $t_{RFC} = 7.8 \mu\text{s}$ "distributed refresh"
- 6) 1.05 mA at $85 \text{ }^\circ\text{C}$, 1.00 mA at $60 \text{ }^\circ\text{C}$



4.2 AC Characteristics

This chapter lists the AC characteristics.

TABLE 13
AC Timing - Absolute Specifications

Parameter	Symbol	-7		-6		Unit	Note ¹⁾²⁾³⁾
		PC143-333		PC166-333			
		Min.	Max.	Min.	Max.		
Clock and Clock Enable							
Clock Frequency	t_{CK}	7 7.5	— —	6 7.5	— —	ns ns	CL3 CL2
Access Time from Clock	t_{AC}	— —	5.4 5.4	— —	5.4 5.4	ns ns	CL3 CL2 3)4)5)
Clock High Pulse Width	t_{CH}	2.5	—	2	—	ns	
Clock Low Pulse Width	t_{CL}	2.5	—	2	—	ns	
Transition time	t_T	0.3	1.2	0.3	1.2	ns	
Setup and Hold Times							
Input Setup Time	t_{IS}	1.5	—	1.5	—	ns	6)
Input Hold Time	t_{IH}	0.8	—	0.8	—	ns	6)
CKE Setup Time	t_{CKS}	1.5	—	1.5	—	ns	6)
CKE Hold Time	t_{CKH}	0.8	—	0.8	—	ns	6)
Mode Register Set-up to Active delay	t_{RSC}	2	—	2	—	t_{CK}	
Power Down Mode Entry Time	t_{SB}	0	7	0	6	ns	
Common Parameters							
Row to Column Delay Time	t_{RCD}	15	—	15	—	ns	7)
Row Precharge Time	t_{RP}	15	—	15	—	ns	7)
Row Active Time	t_{RAS}	37	100k	36	100k	ns	7)
Row Cycle Time	t_{RC}	60	—	60	—	ns	7)
Row Cycle Time during Auto Refresh	t_{RFC}	63	—	60	—	ns	
Activate(a) to Activate(b) Command period	t_{RRD}	14	—	12	—	ns	7)
CAS(a) to CAS(b) Command period	t_{CCD}	1	—	1	—	t_{CK}	
Refresh Cycle							
Refresh Period (8192 cycles)	t_{REF}	—	64	—	64	ms	
Self Refresh Exit Time	t_{SREX}	1	—	1	—	t_{CK}	
Data Out Hold Time	t_{OH}	3	—	2.5	—	ns	3)5)
Read Cycle							
Data Out to Low Impedance Time	t_{LZ}	0	—	0	—	ns	
Data Out to High Impedance Time	t_{HZ}	3	7	3	6	ns	
DQM Data Out Disable Latency	t_{DQZ}	—	2	—	2	t_{CK}	

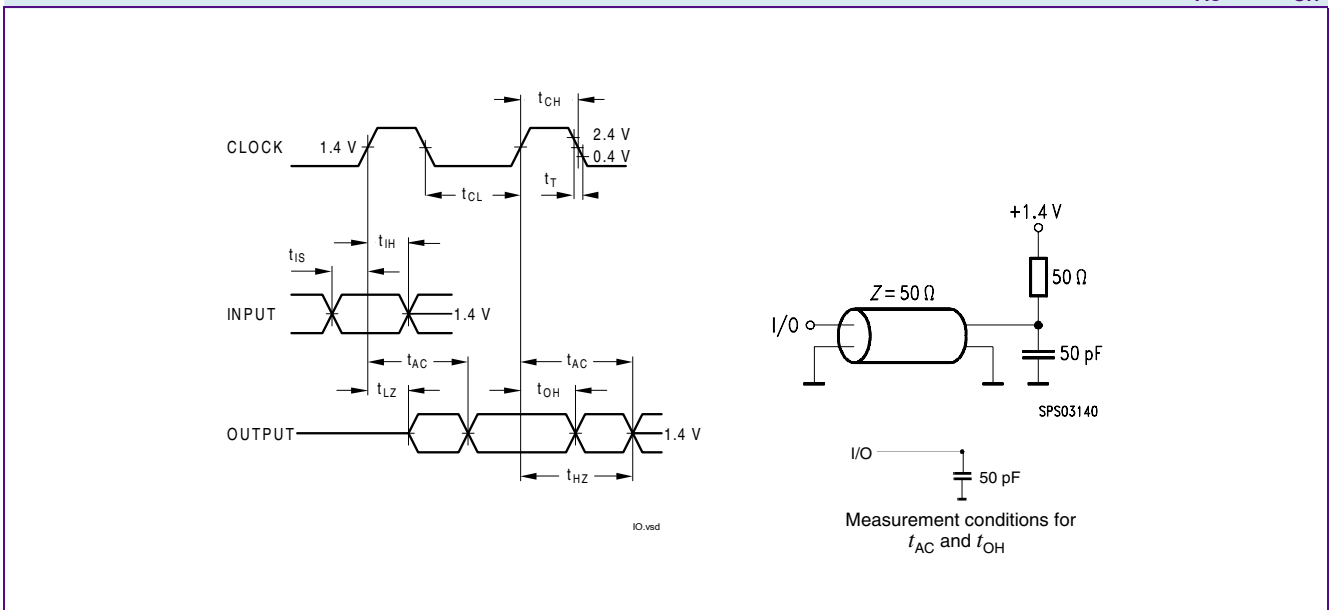


**HY[B/I]39S256[40/80/16][0/7]F[E/T/F](L)
256-MBit Synchronous DRAM**

Parameter	Symbol	-7		-6		Unit	Note ¹⁾²⁾³⁾
		PC143-333		PC166-333			
		Min.	Max.	Min.	Max.		
Write Cycle							
Last Data Input to Precharge (Write without Auto Precharge)	t_{WR}	14	—	12	—	ns	8)
Last Data Input to Activate(Write with Auto Precharge)	$t_{DAL(min.)}$					t_{CK}	9)
DQM Write Mask Latency	t_{DQW}	0	—	0	—	t_{CK}	

- 1) $T_A = 0$ to 70 °C; $V_{SS} = 0$ V; $V_{DD}, V_{DDQ} = 3.3$ V \pm 0.3 V, $t_T = 1$ ns
- 2) For proper power-up see the operation section of this data sheet.
- 3) AC timing tests for LV-TTL versions have $V_{IL} = 0.4$ V and $V_{IH} = 2.4$ V with the timing referenced to the 1.4 V crossover point. The transition time is measured between V_{IH} and V_{IL} . All AC measurements assume $t_T = 1$ ns with the AC output load circuit shown in figure below. Specified t_{AC} and t_{OH} parameters are measured with a 50 pF only, without any resistive termination and with an input signal of 1V / ns edge rate between 0.8 V and 2.0 V.
- 4) If clock rising time is longer than 1 ns, a time $(t_T/2 - 0.5)$ ns has to be added to this parameter.
- 5) Access time from clock t_{ac} is 4.6 ns for PC133 components with no termination and 0 pF load, Data out hold time t_{oh} is 1.8 ns for PC133 components with no termination and 0 pF load.
- 6) If t_T is longer than 1 ns, a time $(t_T - 1)$ ns has to be added to this parameter.
- 7) These parameter account for the number of clock cycles and depend on the operating frequency of the clock, as follows:the number of clock cycles = specified value of timing period (counted in fractions as a whole number)
- 8) It is recommended to use two clock cycles between the last data-in and the precharge command in case of a write command without Auto-Precharge. One clock cycle between the last data-in and the precharge command is also supported, but restricted to cycle times t_{ck} greater or equal the specified t_{WR} value, where t_{ck} is equal to the actual system clock time.
- 9) When a Write command with Auto Precharge has been issued, a time of $t_{DAL(min)}$ has be fulfilled before the next Activate Command can be applied. For each of the terms, if not already an integer, round up to the next highest integer. t_{CK} is equal to the actual system clock time.

FIGURE 5
Measurement conditions for t_{AC} and t_{OH}

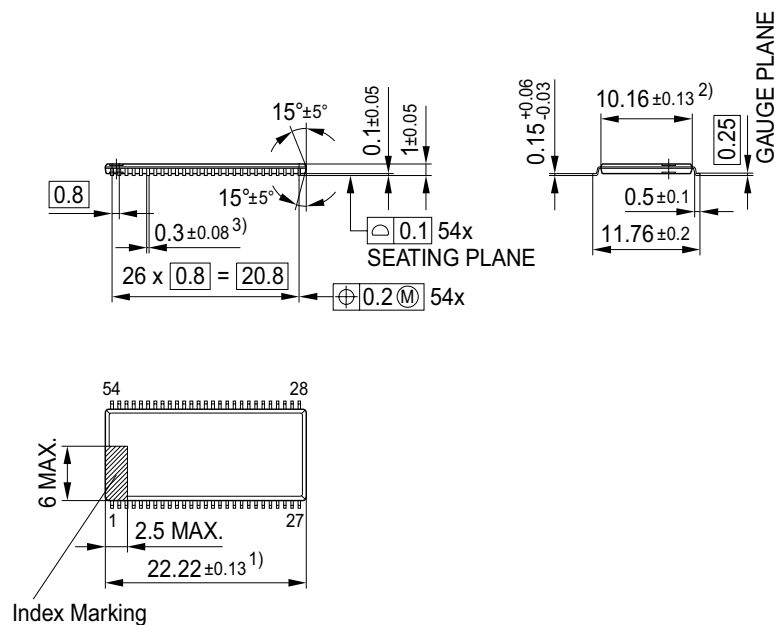


HY[B/I]39S256[40/80/16][0/7]F[E/T/F](L)
256-MBit Synchronous DRAM

5 Package Outlines

This chapter contains the package outlines of the products.

FIGURE 6
Package Outline P(G)-TSOPII-54 (top view)



- 1) Does not include plastic or metal protrusion of 0.15 max. per side
- 2) Does not include plastic protrusion of 0.25 max. per side
- 3) Does not include dambar protrusion of 0.13 max. per side

GPX01088

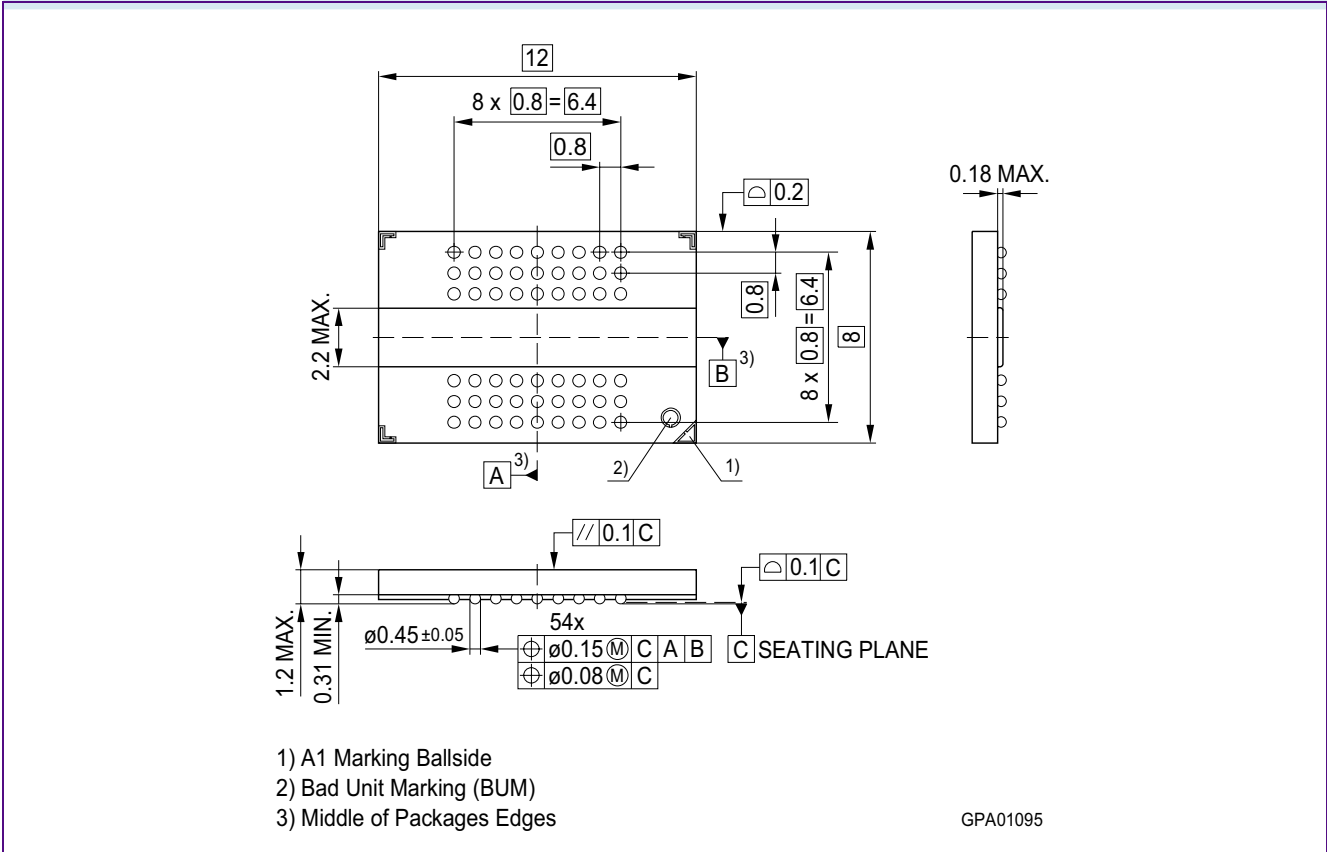
Notes

1. Drawing according to ISO 8015
2. Dimensions in mm
3. General tolerances +/- 0.15



HY[B/I]39S256[40/80/16][0/7]F[E/T/F](L)
256-MBit Synchronous DRAM

FIGURE 7
Package Outline P(G)-TFBGA-54



Notes

1. Drawing according to ISO 8015
2. Dimensions in mm
3. General tolerances +/- 0.15



6 Product Nomenclature

For reference the Qimonda SDRAM component nomenclature is enclosed in this chapter.

TABLE 14
Examples for Nomenclature Fields

Example for	Field Number										
	1	2	3	4	5	6	7	8	9	10	11
SDRAM	HYB	39	S	256	80		0	F	F		-6
SDRAM	HYI	39	S	256	16		0	F	E		-7

TABLE 15
Memory Components

Field	Description	Values	Coding
1	Qimonda Component Prefix	HYB	Memory components
		HYI	Memory components, industrial temperature range (-40°C – +85 °C)
2	Interface Voltage [V]	39	3.3 V
3	DRAM Technology	S	Single Data Rate SDRAM
4	Component Density [Mbit]	128	128 Mbit
		256	256 Mbit
		512	512 Mbit
5+6	Number of I/Os	40	×4
		80	×8
		16	×16
7	Product Variations	0 .. 9	look up table
8	Die Revision	C	Third
		D	Fourth
		F	Fifth
9	Package, Lead-Free Status	E	TSOP, lead- and halogen-free
		F	FBGA, lead- and halogen-free
10	Power	–	Standard power product
11	Speed Grade	-6	PC166-333
		-7	PC143-333, PC133-222

HY[B/I]39S256[40/80/16][0/7]F[E/T/F](L)
256-MBit Synchronous DRAM

List of Figures

Figure 1	Pinouts P(G)-TSOPII-54	9
Figure 2	Ballout for $\times 16$ components, TFBGA-54 (top view)	10
Figure 3	Ballout for $\times 8$ components, TFBGA-54 (top view)	11
Figure 4	Ballout for $\times 4$ components, TFBGA-54 (top view)	12
Figure 5	Measurement conditions for t_{AC} and t_{OH}	20
Figure 6	Package Outline P(G)-TSOPII-54 (top view)	21
Figure 7	Package Outline P(G)-TFBGA-54	22

HY[B/I]39S256[40/80/16][0/7]F[E/T/F](L)
256-MBit Synchronous DRAM

List of Tables

Table 1	Performance	3
Table 2	Ordering Information for RoHS Compliant Products	4
Table 3	Ordering Information for Lead-Containing Products	5
Table 4	Pin Configuration of the SDRAM	6
Table 5	Truth Table: Operation Command	13
Table 6	Mode Register Definition ($BA_{1:0} = 00_B$)	14
Table 7	Burst Length and Sequence	15
Table 8	Absolute Maximum Ratings	16
Table 9	DC Characteristics	17
Table 10	Input and Output Capacitances	17
Table 11	IDD Conditions	17
Table 12	I_{DD} Specifications and Conditions	18
Table 13	AC Timing - Absolute Specifications	19
Table 14	Examples for Nomenclature Fields	23
Table 15	Memory Components	23

HY[B/I]39S256[40/80/16][0/7]F[E/T/F](L)
256-MBit Synchronous DRAM

Table of Contents

1	Overview	3
1.1	Features	3
1.2	Description	4
2	Configuration	6
2.1	Pin Description	6
2.2	Package P(G)-TSOPII-54	9
2.3	Package PG-TFBGA-54	10
3	Functional Description	13
4	Electrical Characteristics	16
4.1	Operating Conditions	16
4.2	AC Characteristics	19
5	Package Outlines	21
6	Product Nomenclature	23
	List of Figures	24
	List of Tables	25
	Table of Contents	26

Edition 2007-09
Published by Qimonda AG
Gustav-Heinemann-Ring 212
D-81739 München, Germany
© Qimonda AG 2007.
All Rights Reserved.

Legal Disclaimer

The information given in this Internet Data Sheet shall in no event be regarded as a guarantee of conditions or characteristics ("Beschaffenheitsgarantie"). With respect to any examples or hints given herein, any typical values stated herein and/or any information regarding the application of the device, Qimonda hereby disclaims any and all warranties and liabilities of any kind, including without limitation warranties of non-infringement of intellectual property rights of any third party.

Information

For further information on technology, delivery terms and conditions and prices please contact your nearest Qimonda Office.

Warnings

Due to technical requirements components may contain dangerous substances. For information on the types in question please contact your nearest Qimonda Office.

Qimonda Components may only be used in life-support devices or systems with the express written approval of Qimonda, if a failure of such components can reasonably be expected to cause the failure of that life-support device or system, or to affect the safety or effectiveness of that device or system. Life support devices or systems are intended to be implanted in the human body, or to support and/or maintain and sustain and/or protect human life. If they fail, it is reasonable to assume that the health of the user or other persons may be endangered.